

# Declaration of conformity



**We, :** WONWOO Engineering Co., Ltd.

4F 403, Bucheon Techno-park 193, Yakdae-dong, Wonmi-gu,  
Bucheon-city, Gyeonggi-do, 470-734, Korea

Declare under our sole responsibility that Multifunctional CCTV Tester (for those models listed below), as delivered, are in conformity with the following European Directives:

**ELECTROMAGNETIC COMPATIBILITY DIRECTIVE, 2004/108/EC**

**Low Voltage Directive 2006/95/EC**

**(As amended by 92/31/EEC and by Article 5 of 93/68/EEC)**

**Per the provisions of:**

EN 61326-1:2006

IEC 61010-1:2001 (2<sup>nd</sup> Edition); EN 61010-1:2001 (2<sup>nd</sup> Edition)

Multifunctional CCTV Tester

**Product Name**

RAPPORT II. PRO

**Model Number**

**Year CE Marking was affixed : 2008**

Any modification or the above product(s), unwarranted by the above manufacturer, will nullify this declaration.

Manufacturer : position

Name

Test by : Dastek EMC & Safety Lab in Korea

Report No : DAC08-0172, DAC08-0181

**Laboratory Chief**

**In-Young, CHUNG**





## TEST REPORT

### DASTEK EMC&SAFETY Lab.

204-4, Chuge-Ri, Yangji-Myen,  
Cheoin-Gu, Yongin-Si,  
Kyounggi-Do, Korea.

T e l : 82-31-335-9341

F a x : 82-31-335-9343

E-mail: [dataup@dastek.co.kr](mailto:dataup@dastek.co.kr)

Report Number: DAC08-0173

Date of issue: 2008/05/26

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Applicant : WONWOO ENGINEERING CO., LTD.  
Manufacturer : WONWOO ENGINEERING CO., LTD.  
Product Type : Multifunctional CCTV Tester  
Model Name : RAPPORT II. PRO  
Serial No. : N/A

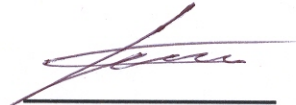
This device was tested in compliance with  
the FCC Part 15 Subpart B.

This laboratory is accredited for the above test item(s) and test method(s)  
by Korea Laboratory Accreditation Scheme (KOLAS), which is  
a signatory to the International Laboratory Accreditation Cooperation (ILAC)  
Mutual Recognition Arrangement (MRA).


The test result only responds to the tested sample. It is not allowed to copy  
this report even partly without the allowance of the test laboratory.

TEST RESULT : ☒ PASS ☐ FAIL

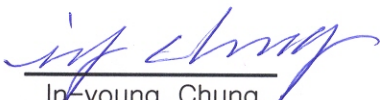
EMC Test Engineer

  
Dong-hun, Jang

Technical Manager

  
Chang-hun, Lee

Laboratory Chief

  
In-young, Chung

